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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	120MHz
Connectivity	CANbus, Ethernet, I²C, IrDA, LINbus, Memory Card, SPI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, I²S, LCD, POR, PWM, WDT
Number of I/O	140
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	132K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 24x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	201-UFBGA
Supplier Device Package	176+25UFBGA (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f207igh7

3.4 Embedded Flash memory

The STM32F20x devices embed a 128-bit wide Flash memory of 128 Kbytes, 256 Kbytes, 512 Kbytes, 768 Kbytes or 1 Mbyte available for storing programs and data.

The devices also feature 512 bytes of OTP memory that can be used to store critical user data such as Ethernet MAC addresses or cryptographic keys.

3.5 CRC (cyclic redundancy check) calculation unit

The CRC (cyclic redundancy check) calculation unit is used to get a CRC code from a 32-bit data word and a fixed generator polynomial.

Among other applications, CRC-based techniques are used to verify data transmission or storage integrity. In the scope of the EN/IEC 60335-1 standard, they offer a means of verifying the Flash memory integrity. The CRC calculation unit helps compute a software signature during runtime, to be compared with a reference signature generated at link-time and stored at a given memory location.

3.6 Embedded SRAM

All STM32F20x products embed:

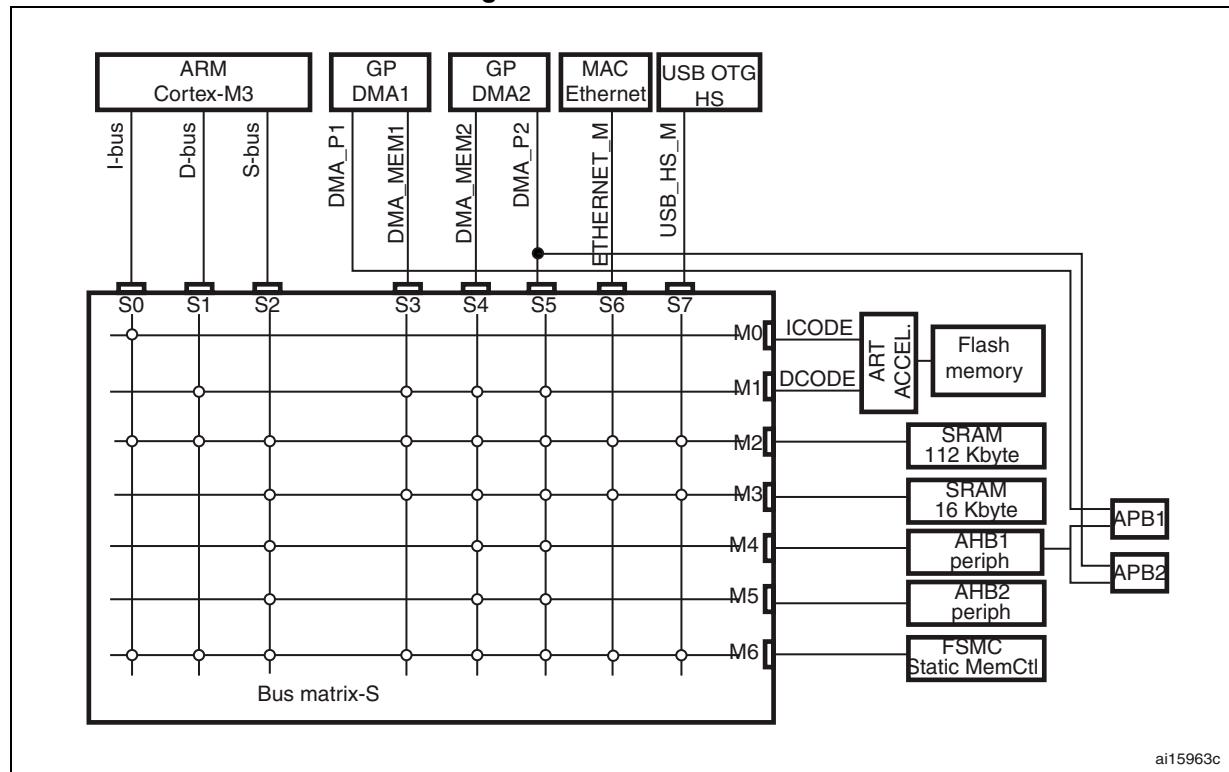
- Up to 128 Kbytes of system SRAM accessed (read/write) at CPU clock speed with 0 wait states
- 4 Kbytes of backup SRAM.

The content of this area is protected against possible unwanted write accesses, and is retained in Standby or VBAT mode.

3.7 Multi-AHB bus matrix

The 32-bit multi-AHB bus matrix interconnects all the masters (CPU, DMAs, Ethernet, USB HS) and the slaves (Flash memory, RAM, FSMC, AHB and APB peripherals) and ensures a seamless and efficient operation even when several high-speed peripherals work simultaneously.

Figure 5. Multi-AHB matrix



3.8 DMA controller (DMA)

The devices feature two general-purpose dual-port DMAs (DMA1 and DMA2) with 8 streams each. They are able to manage memory-to-memory, peripheral-to-memory and memory-to-peripheral transfers. They share some centralized FIFOs for APB/AHB peripherals, support burst transfer and are designed to provide the maximum peripheral bandwidth (AHB/APB).

The two DMA controllers support circular buffer management, so that no specific code is needed when the controller reaches the end of the buffer. The two DMA controllers also have a double buffering feature, which automates the use and switching of two memory buffers without requiring any special code.

Each stream is connected to dedicated hardware DMA requests, with support for software trigger on each stream. Configuration is made by software and transfer sizes between source and destination are independent.

Table 8. STM32F20x pin and ball definitions (continued)

Pins						Pin name (function after reset) ⁽¹⁾	Pin type	I/O structure	Note	Alternate functions	Additional functions
LQFP64	WL-CSP64+2	LQFP100	LQFP144	LQFP176	UFBGA176						
-	-	-	-	130	D13	PH15	I/O	FT	-	TIM8_CH3N, DCMI_D11, EVENTOUT	-
-	-	-	-	131	E14	PI0	I/O	FT	-	TIM5_CH4, SPI2_NSS, I2S2_WS, DCMI_D13, EVENTOUT	-
-	-	-	-	132	D14	PI1	I/O	FT	-	SPI2_SCK, I2S2_SCK, DCMI_D8, EVENTOUT	-
-	-	-	-	133	C14	PI2	I/O	FT	-	TIM8_CH4 ,SPI2_MISO, DCMI_D9, EVENTOUT	-
-	-	-	-	134	C13	PI3	I/O	FT	-	TIM8_ETR, SPI2_MOSI, I2S2_SD, DCMI_D10, EVENTOUT	-
-	-	-	-	135	D9	V _{SS}	S	-	-	-	-
-	-	-	-	136	C9	V _{DD}	S	-	-	-	-
49	A1	76	109	137	A14	PA14 (JTCK-SWCLK)	I/O	FT	-	JTCK-SWCLK, EVENTOUT	-
50	A2	77	110	138	A13	PA15 (JTDI)	I/O	FT	-	JTDI, SPI3_NSS, I2S3_WS,TIM2_CH1_ETR, SPI1 NSS, EVENTOUT	-
51	B3	78	111	139	B14	PC10	I/O	FT	-	SPI3_SCK, I2S3_SCK, UART4_TX, SDIO_D2, DCMI_D8, USART3_RX, EVENTOUT	-
52	C3	79	112	140	B13	PC11	I/O	FT	-	UART4_RX, SPI3_MISO, SDIO_D3, DCMI_D4,USART3_RX, EVENTOUT	-
53	A3	80	113	141	A12	PC12	I/O	FT	-	UART5_TX, SDIO_CK, DCMI_D9, SPI3_MOSI, I2S3_SD, USART3_CK, EVENTOUT	-
-	-	81	114	142	B12	PD0	I/O	FT	-	FSMC_D2,CAN1_RX, EVENTOUT	-
-	-	82	115	143	C12	PD1	I/O	FT	-	FSMC_D3, CAN1_TX, EVENTOUT	-

6.3.3 Operating conditions at power-up / power-down (regulator ON)

Subject to general operating conditions for T_A .

Table 17. Operating conditions at power-up / power-down (regulator ON)

Symbol	Parameter	Min	Max	Unit
t_{VDD}	V_{DD} rise time rate	20	∞	$\mu\text{s}/\text{V}$
	V_{DD} fall time rate	20	∞	

6.3.4 Operating conditions at power-up / power-down (regulator OFF)

Subject to general operating conditions for T_A .

Table 18. Operating conditions at power-up / power-down (regulator OFF)

Symbol	Parameter	Conditions	Min	Max	Unit
t_{VDD}	V_{DD} rise time rate	Power-up	20	∞	$\mu\text{s}/\text{V}$
	V_{DD} fall time rate	Power-down	20	∞	
t_{VCAP}	V_{CAP_1} and V_{CAP_2} rise time rate	Power-up	20	∞	$\mu\text{s}/\text{V}$
	V_{CAP_1} and V_{CAP_2} fall time rate	Power-down	20	∞	

Table 26. Peripheral current consumption (continued)

Peripheral ⁽¹⁾	Typical consumption at 25 °C	Unit
APB1	TIM2	0.61
	TIM3	0.49
	TIM4	0.54
	TIM5	0.62
	TIM6	0.20
	TIM7	0.20
	TIM12	0.36
	TIM13	0.28
	TIM14	0.25
	USART2	0.25
	USART3	0.25
	UART4	0.25
	UART5	0.26
	I2C1	0.25
	I2C2	0.25
	I2C3	0.25
	SPI2	0.20/0.10
	SPI3	0.18/0.09
	CAN1	0.31
	CAN2	0.30
	DAC channel 1 ⁽²⁾	1.11
	DAC channel 1 ⁽³⁾	1.11
	PWR	0.15
	WWDG	0.15

Table 34. Main PLL characteristics (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Jitter ⁽³⁾	Cycle-to-cycle jitter	System clock 120 MHz	RMS	-	25	-
			peak to peak	-	± 150	-
			RMS	-	15	-
	Period Jitter	System clock 120 MHz	peak to peak	-	± 200	-
	Main clock output (MCO) for RMII Ethernet		Cycle to cycle at 50 MHz on 1000 samples	-	32	-
	Main clock output (MCO) for MII Ethernet		Cycle to cycle at 25 MHz on 1000 samples	-	40	-
	Bit Time CAN jitter	Cycle to cycle at 1 MHz on 1000 samples	-	330	-	
I _{DD(PLL)} ⁽⁴⁾	PLL power consumption on VDD	VCO freq = 192 MHz VCO freq = 432 MHz	0.15 0.45	-	0.40 0.75	mA
I _{DDA(PLL)} ⁽⁴⁾	PLL power consumption on VDDA	VCO freq = 192 MHz VCO freq = 432 MHz	0.30 0.55	-	0.40 0.85	mA

- Take care of using the appropriate division factor M to obtain the specified PLL input clock values. The M factor is shared between PLL and PLLI2S.
- Guaranteed by design, not tested in production.
- The use of 2 PLLs in parallel could degrade the Jitter up to +30%.
- Guaranteed by characterization results, not tested in production.

Table 35. PLLI2S (audio PLL) characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f _{PLLI2S_IN}	PLLI2S input clock ⁽¹⁾	-	0.95 ⁽²⁾	1	2.10 ⁽²⁾	MHz
f _{PLLI2S_OUT}	PLLI2S multiplier output clock	-	-	-	216	MHz
f _{VCO_OUT}	PLLI2S VCO output	-	192	-	432	MHz
t _{LOCK}	PLLI2S lock time	VCO freq = 192 MHz	75	-	200	μ s
		VCO freq = 432 MHz	100	-	300	

6.3.11 PLL spread spectrum clock generation (SSCG) characteristics

The spread spectrum clock generation (SSCG) feature allows to reduce electromagnetic interferences (see [Table 42: EMI characteristics](#)). It is available only on the main PLL.

Table 36. SSCG parameters constraint

Symbol	Parameter	Min	Typ	Max ⁽¹⁾	Unit
f _{Mod}	Modulation frequency	-	-	10	KHz
md	Peak modulation depth	0.25	-	2	%
MODEPER * INCSTEP	-	-	-	2 ¹⁵ -1	-

1. Guaranteed by design, not tested in production.

Equation 1

The frequency modulation period (MODEPER) is given by the equation below:

$$\text{MODEPER} = \text{round}[f_{\text{PLL_IN}} / (4 \times f_{\text{Mod}})]$$

f_{PLL_IN} and f_{Mod} must be expressed in Hz.

As an example:

If f_{PLL_IN} = 1 MHz and f_{MOD} = 1 kHz, the modulation depth (MODEPER) is given by equation 1:

$$\text{MODEPER} = \text{round}[10^6 / (4 \times 10^3)] = 250$$

Equation 2

Equation 2 allows to calculate the increment step (INCSTEP):

$$\text{INCSTEP} = \text{round}[(2^{15}-1) \times md \times \text{PLLN} / (100 \times 5 \times \text{MODEPER})]$$

f_{VCO_OUT} must be expressed in MHz.

With a modulation depth (md) = ±2 % (4 % peak to peak), and PLLN = 240 (in MHz):

$$\text{INCSTEP} = \text{round}[(2^{15}-1) \times 2 \times 240 / (100 \times 5 \times 250)] = 126 \text{md(quantitized)}\%$$

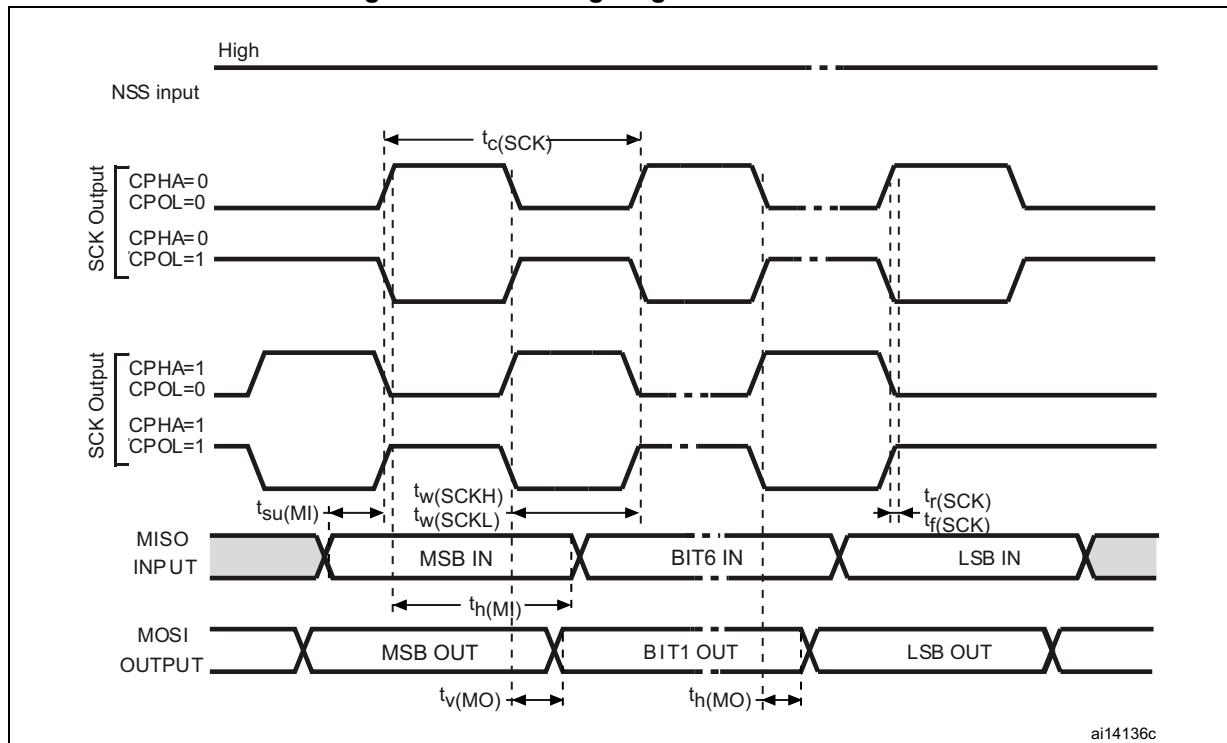
An amplitude quantization error may be generated because the linear modulation profile is obtained by taking the quantized values (rounded to the nearest integer) of MODPER and INCSTEP. As a result, the achieved modulation depth is quantized. The percentage quantized modulation depth is given by the following formula:

$$md_{\text{quantized}}\% = (\text{MODEPER} \times \text{INCSTEP} \times 100 \times 5) / ((2^{15}-1) \times \text{PLLN})$$

As a result:

$$md_{\text{quantized}}\% = (250 \times 126 \times 100 \times 5) / ((2^{15}-1) \times 240) = 2.0002\%(\text{peak})$$

Figure 44. SPI timing diagram - master mode



[Table 65](#) gives the list of Ethernet MAC signals for MII and [Figure 50](#) shows the corresponding timing diagram.

Figure 51. Ethernet MII timing diagram

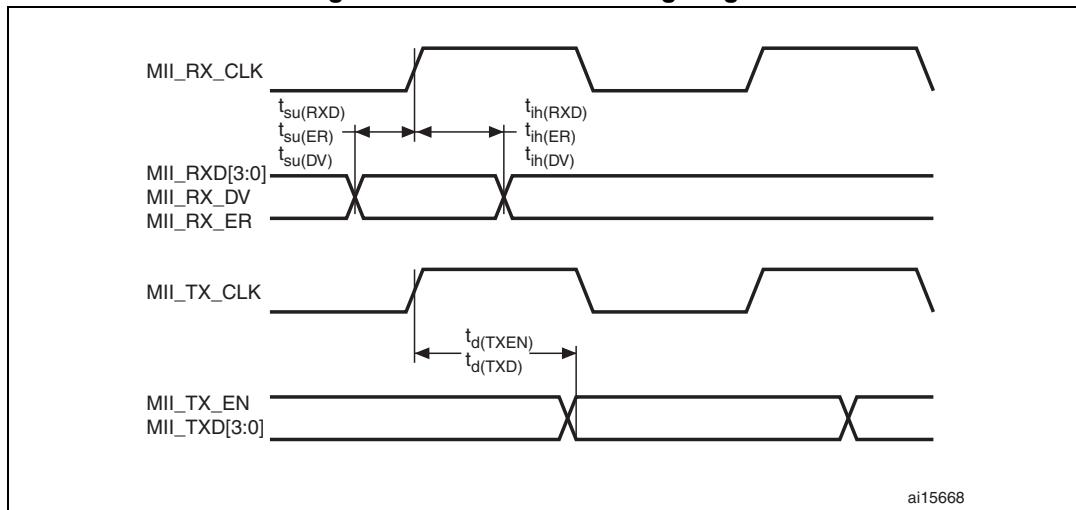
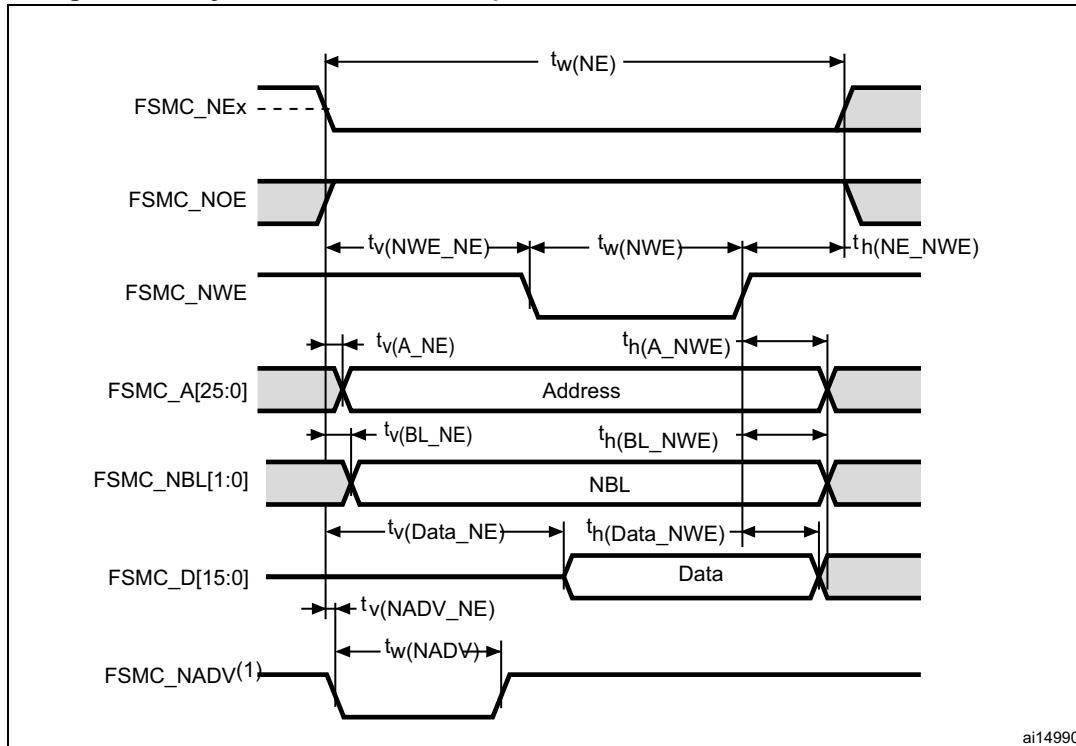


Table 65. Dynamics characteristics: Ethernet MAC signals for MII

Symbol	Rating	Min	Typ	Max	Unit
$t_{su(RXD)}$	Receive data setup time	7.5	-	-	ns
$t_{ih(RXD)}$	Receive data hold time	1	-	-	ns
$t_{su(DV)}$	Data valid setup time	4	-	-	ns
$t_{ih(DV)}$	Data valid hold time	0	-	-	ns
$t_{su(ER)}$	Error setup time	3.5	-	-	ns
$t_{ih(ER)}$	Error hold time	0	-	-	ns
$t_{d(TXEN)}$	Transmit enable valid delay time	-	11	14	ns
$t_{d(TXD)}$	Transmit data valid delay time	-	11	14	ns

CAN (controller area network) interface

Refer to [Section 6.3.16: I/O port characteristics](#) for more details on the input/output alternate function characteristics (CANTX and CANRX).

Figure 58. Asynchronous non-multiplexed SRAM/PSRAM/NOR write waveforms

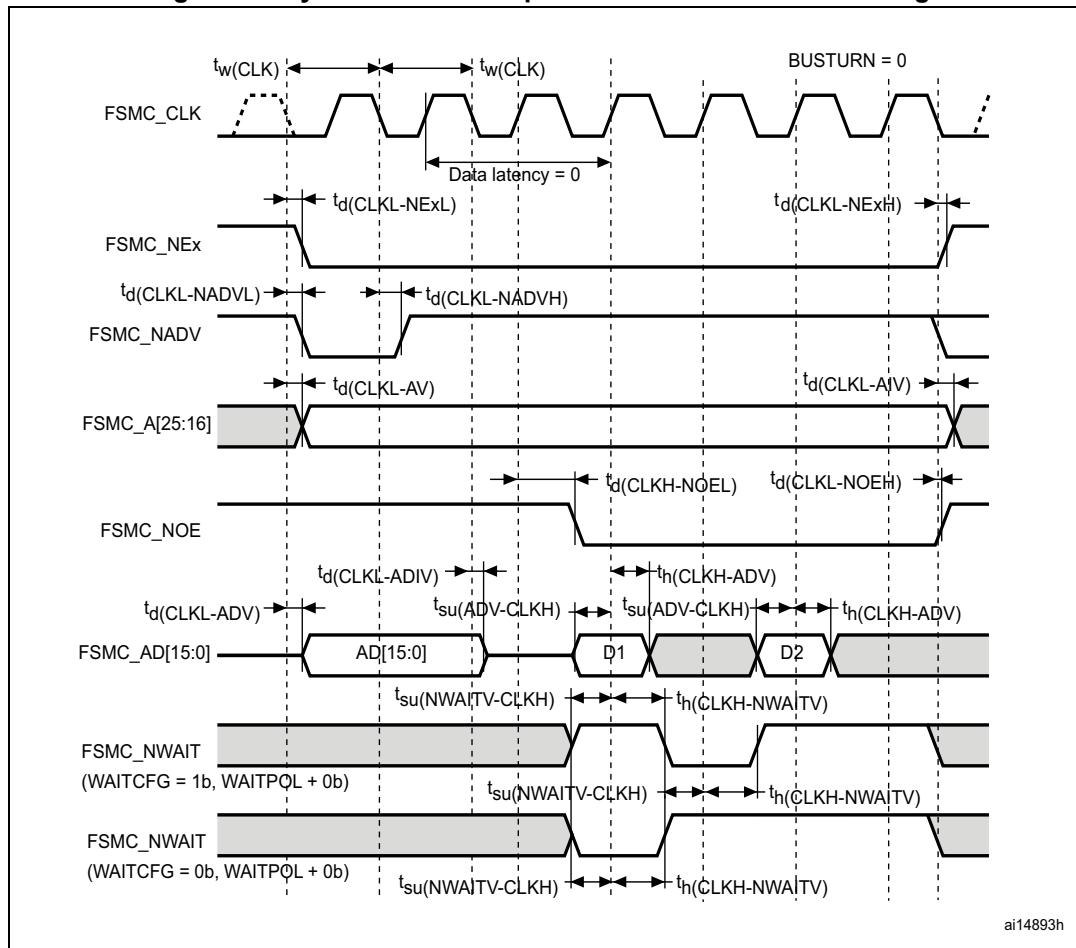
1. Mode 2/B, C and D only. In Mode 1, FSMC_NADV is not used.

Table 73. Asynchronous non-multiplexed SRAM/PSRAM/NOR write timings⁽¹⁾⁽²⁾

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FSMC_NE low time	$3T_{HCLK}$	$3T_{HCLK} + 4$	ns
$t_{v(NWE_NE)}$	FSMC_NEx low to FSMC_NWE low	$T_{HCLK} - 0.5$	$T_{HCLK} + 0.5$	ns
$t_{w(NWE)}$	FSMC_NWE low time	$T_{HCLK} - 0.5$	$T_{HCLK} + 3$	ns
$t_{h(NE_NWE)}$	FSMC_NWE high to FSMC_NE high hold time	T_{HCLK}	-	ns
$t_{v(A_NE)}$	FSMC_NEx low to FSMC_A valid	-	0	ns
$t_{h(A_NWE)}$	Address hold time after FSMC_NWE high	$T_{HCLK} - 3$	-	ns
$t_{v(BL_NE)}$	FSMC_NEx low to FSMC_BL valid	-	0.5	ns
$t_{h(BL_NWE)}$	FSMC_BL hold time after FSMC_NWE high	$T_{HCLK} - 1$	-	ns
$t_{v(Data_NE)}$	Data to FSMC_NEx low to Data valid	-	$T_{HCLK} + 5$	ns
$t_{h(Data_NWE)}$	Data hold time after FSMC_NWE high	$T_{HCLK} + 0.5$	-	ns
$t_{v(NADV_NE)}$	FSMC_NEx low to FSMC_NADV low	-	2	ns
$t_{w(NADV)}$	FSMC_NADV low time	-	$T_{HCLK} + 1.5$	ns

1. $C_L = 30 \text{ pF}$.
2. Guaranteed by characterization results, not tested in production.

Figure 61. Synchronous multiplexed NOR/PSRAM read timings

Table 76. Synchronous multiplexed NOR/PSRAM read timings⁽¹⁾⁽²⁾

Symbol	Parameter	Min	Max	Unit
$t_w(CLK)$	FSMC_CLK period	$2T_{HCLK}$	-	ns
$t_d(CLKL-NExL)$	FSMC_CLK low to FSMC_NEx low ($x=0..2$)	-	0	ns
$t_d(CLKL-NExH)$	FSMC_CLK low to FSMC_NEx high ($x= 0...2$)	1	-	ns
$t_d(CLKL-NADVL)$	FSMC_CLK low to FSMC_NADV low	-	1.5	ns
$t_d(CLKL-NADVH)$	FSMC_CLK low to FSMC_NADV high	2.5	-	ns
$t_d(CLKL-AV)$	FSMC_CLK low to FSMC_Ax valid ($x=16...25$)	-	0	ns
$t_d(CLKL-AIV)$	FSMC_CLK low to FSMC_Ax invalid ($x=16...25$)	0	-	ns
$t_d(CLKH-NOEL)$	FSMC_CLK high to FSMC_NOE low	-	1	ns
$t_d(CLKL-NOEH)$	FSMC_CLK low to FSMC_NOE high	1	-	ns
$t_d(CLKL-ADV)$	FSMC_CLK low to FSMC_AD[15:0] valid	-	3	ns
$t_d(CLKL-ADIV)$	FSMC_CLK low to FSMC_AD[15:0] invalid	0	-	ns

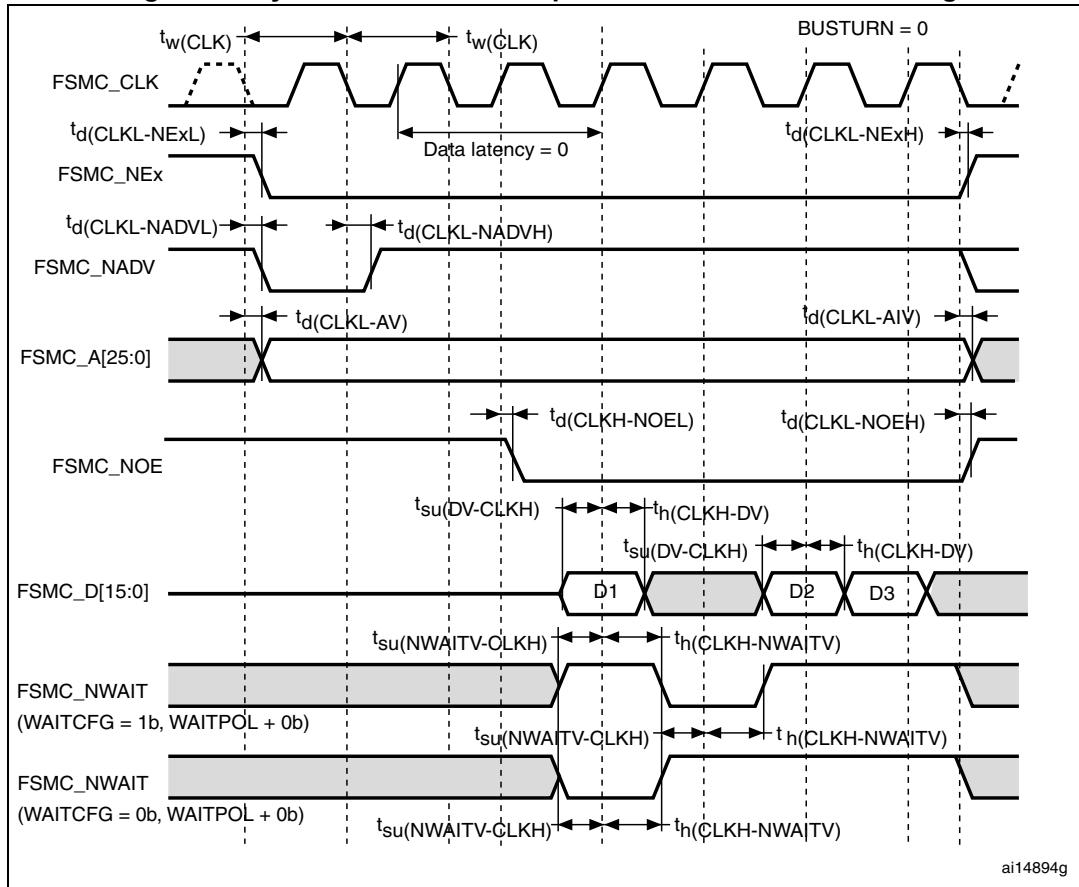
Table 77. Synchronous multiplexed PSRAM write timings⁽¹⁾⁽²⁾ (continued)

Symbol	Parameter	Min	Max	Unit
$t_d(CLKL-NWEL)$	FSMC_CLK low to FSMC_NWE low	-	1	ns
$t_d(CLKL-NWEH)$	FSMC_CLK low to FSMC_NWE high	0	-	ns
$t_d(CLKL-ADIV)$	FSMC_CLK low to FSMC_AD[15:0] invalid	0	-	ns
$t_d(CLKL-DATA)$	FSMC_A/D[15:0] valid data after FSMC_CLK low	-	2	ns
$t_d(CLKL-NBLH)$	FSMC_CLK low to FSMC_NBL high	0.5	-	ns

1. $C_L = 30 \text{ pF}$.

2. Guaranteed by characterization results, not tested in production.

Figure 63. Synchronous non-multiplexed NOR/PSRAM read timings

Table 78. Synchronous non-multiplexed NOR/PSRAM read timings⁽¹⁾⁽²⁾

Symbol	Parameter	Min	Max	Unit
$t_w(CLK)$	FSMC_CLK period	$2T_{HCLK}$	-	ns
$t_d(CLKL-NExL)$	FSMC_CLK low to FSMC_NEx low ($x=0..2$)	-	0	ns
$t_d(CLKL-NExH)$	FSMC_CLK low to FSMC_NEx high ($x=0..2$)	1	-	ns
$t_d(CLKL-NADVL)$	FSMC_CLK low to FSMC_NADV low	-	2.5	ns

Table 83. Switching characteristics for NAND Flash write cycles⁽¹⁾⁽²⁾

Symbol	Parameter	Min	Max	Unit
$t_w(\text{NWE})$	FSMC_NWE low width	$4T_{\text{HCLK}} - 1$	$4T_{\text{HCLK}} + 3$	ns
$t_v(\text{NWE-D})$	FSMC_NWE low to FSMC_D[15-0] valid	-	0	ns
$t_h(\text{NWE-D})$	FSMC_NWE high to FSMC_D[15-0] invalid	$3T_{\text{HCLK}}$	-	ns
$t_d(\text{D-NWE})$	FSMC_D[15-0] valid before FSMC_NWE high	$5T_{\text{HCLK}}$	-	ns
$t_d(\text{ALE-NWE})$	FSMC_ALE valid before FSMC_NWE low	-	$3T_{\text{HCLK}} + 2$	ns
$t_h(\text{NWE-ALE})$	FSMC_NWE high to FSMC_ALE invalid	$3T_{\text{HCLK}} - 2$	-	ns

1. $C_L = 30 \text{ pF}$.

2. Guaranteed by characterization results, not tested in production.

6.3.26 Camera interface (DCMI) timing specifications

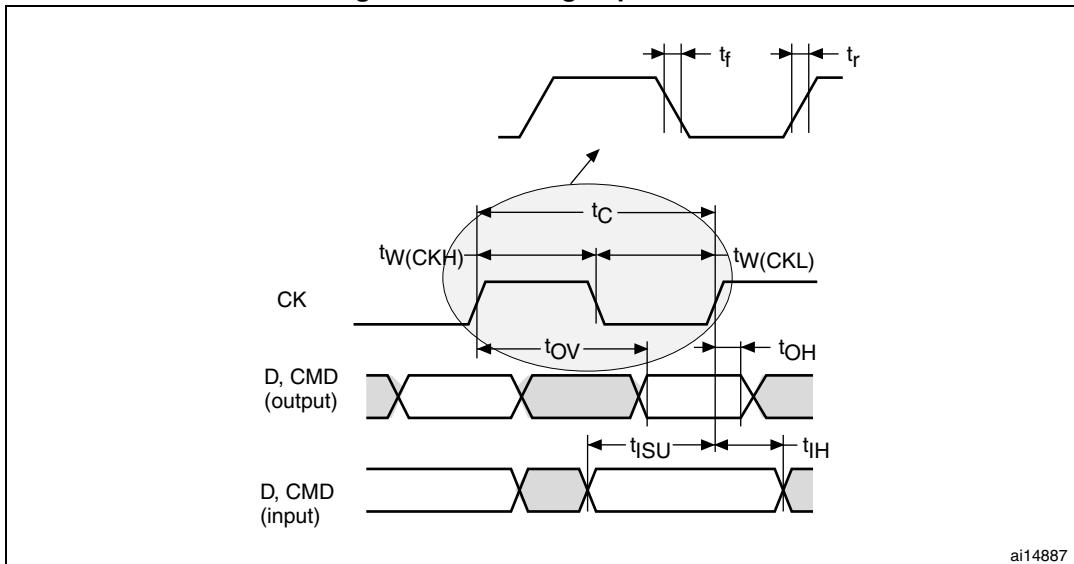
Table 84. DCMI characteristics

Symbol	Parameter	Conditions	Min	Max
-	Frequency ratio DCMI_PIXCLK/f _{HCLK}	DCMI_PIXCLK = 48 MHz	-	0.4

6.3.27 SD/SDIO MMC card host interface (SDIO) characteristics

Unless otherwise specified, the parameters given in [Table 85](#) are derived from tests performed under ambient temperature, f_{PCLKx} frequency and V_{DD} supply voltage conditions summarized in [Table 14](#).

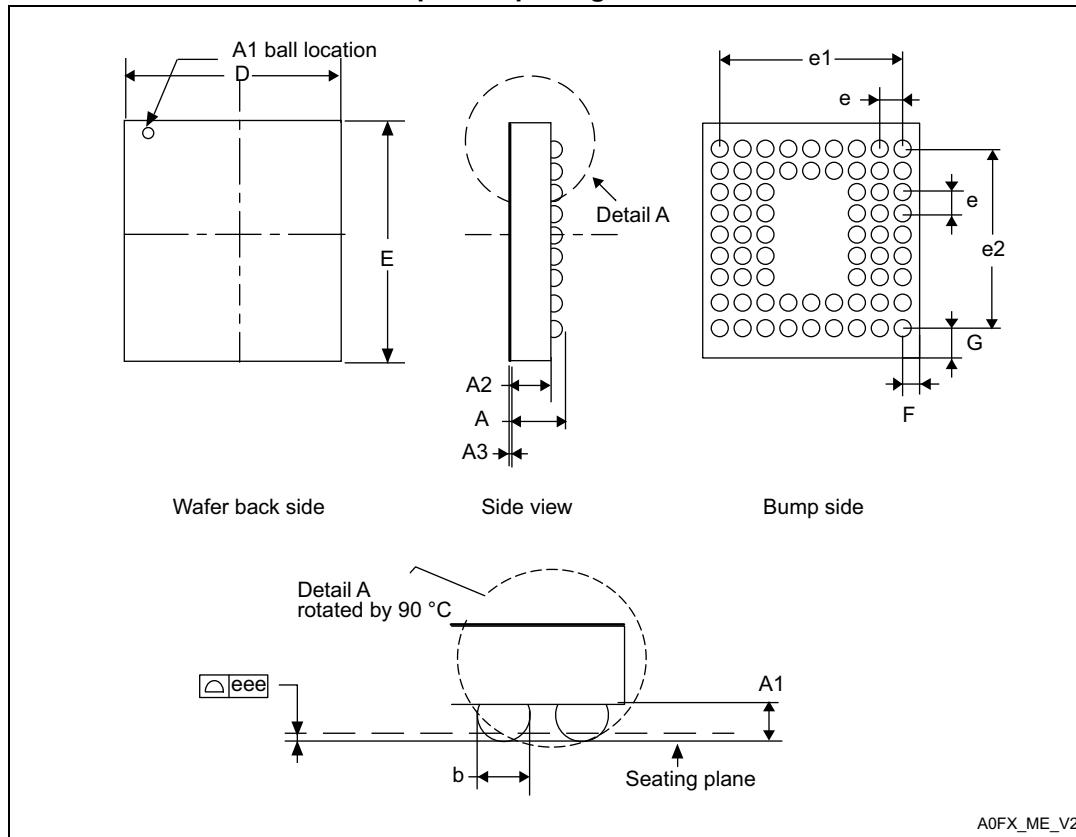
Refer to [Section 6.3.16: I/O port characteristics](#) for more details on the input/output alternate function characteristics (D[7:0], CMD, CK).

Figure 75. SDIO high-speed mode

ai14887

7.2 WLCSP64+2 package information

Figure 79. WLCSP64+2 - 66-ball, 3.639 x 3.971 mm, 0.4 mm pitch wafer level chip scale package outline



1. Drawing is not to scale.

Table 88. WLCSP64+2 - 66-ball, 4.539 x 4.911 mm, 0.4 mm pitch wafer level chip scale package mechanical data

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	0.540	0.570	0.600	0.0213	0.0224	0.0236
A1	-	0.190	-	-	0.0075	-
A2	-	0.380	-	-	0.0150	-
A3	-	0.025	-	-	0.010	-
b ⁽²⁾	0.240	0.270	0.300	0.0094	0.0106	0.0118
D	3.604	3.939	3.674	0.1419	0.1551	0.1446
E	3.936	3.971	4.006	0.1550	0.1563	0.1577
e	-	0.400	-	-	0.0157	-
e1	-	3.200	-	-	0.1260	-
e2	-	3.200	-	-	0.1260	-